[MOSFET](#) – Power, Single N-Channel

60 V, 4.0 mΩ, 100 A

NVMYS4D1N06CL

Features

- Small Footprint (5x6 mm) for Compact Design
- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- LFPAK4 Package, Industry Standard
- AEC−Q101 Qualified and PPAP Capable
- These Devices are Pb−Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

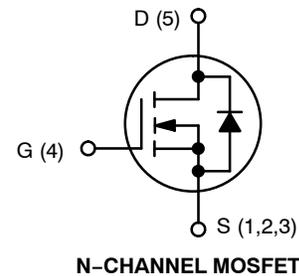| Parameter			Symbol	Value	Unit
Drain−to−Source Voltage			V_{DSS}	60	V
Gate−to−Source Voltage			V_{GS}	±20	V
Continuous Drain Current $R_{θJC}$ (Notes 1, 2, 3)	Steady State	T_C = 25°C	I_D	100	A
		T_C = 100°C		71	
Power Dissipation $R_{θJC}$ (Notes 1, 2)		T_C = 25°C	P_D	79	W
		T_C = 100°C		40	
Continuous Drain Current $R_{θJA}$ (Notes 1, 2, 3)	Steady State	T_A = 25°C	I_D	22	A
		T_A = 100°C		15	
Power Dissipation $R_{θJA}$ (Notes 1, 2)		T_A = 25°C	P_D	3.7	W
		T_A = 100°C		1.8	
Pulsed Drain Current	T_A = 25°C, t_p = 10 μs		I_{DM}	820	A
Operating Junction and Storage Temperature Range			T_J, T_{stg}	−55 to +175	°C
Source Current (Body Diode)			I_S	100	A
Single Pulse Drain−to−Source Avalanche Energy (T_J = 25°C, $I_{L(pk)}$ = 5 A)			E_{AS}	185	mJ
Lead Temperature for Soldering Purposes (1/8″ from case for 10 s)			T_L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

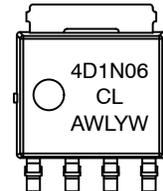| Parameter	Symbol	Value	Unit
Junction−to−Case – Steady State	$R_{θJC}$	1.9	°C/W
Junction−to−Ambient – Steady State (Note 2)	$R_{θJA}$	39	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
2. Surface−mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

ON Semiconductor®

$V_{(BR)DSS}$	$R_{DS(ON)}$ MAX	I_D MAX
60 V	4.0 mΩ @ 10 V	100 A
	5.7 mΩ @ 4.5 V	

N−CHANNEL MOSFET

MARKING DIAGRAM

LFPAK4 CASE 760AB

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4D1N06
  CL
AWLYW
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4D1N06CL	= Specific Device Code
A	= Assembly Location
WL	= Wafer Lot
Y	= Year
W	= Work Week

ORDERING INFORMATION

NVMYS4D1N06CL

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Typ	Max	Unit
OFF CHARACTERISTICS							
Drain−to−Source Breakdown Voltage	$V_{(BR)DSS}$	V_{GS} = 0 V, I_D = 250 μA		60			V
Drain−to−Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}/T_J$				28		mV/°C
Zero Gate Voltage Drain Current	I_{DSS}	V_{GS} = 0 V, V_{DS} = 48 V	T_J = 25°C			10	μA
			T_J = 125°C			250	
Gate−to−Source Leakage Current	I_{GSS}	V_{DS} = 0 V, V_{GS} = 20 V				100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	$V_{GS(TH)}$	V_{GS} = V_{DS}, I_D = 80 μA		1.2		2.0	V
Negative Threshold Temperature Coefficient	$V_{GS(TH)}/T_J$				−5.4		mV/°C
Drain−to−Source On Resistance	$R_{DS(on)}$	V_{GS} = 10 V	I_D = 50 A		3.3	4.0	mΩ
		V_{GS} = 4.5 V	I_D = 50 A		4.6	5.7	
Forward Transconductance	g_{FS}	V_{DS} = 15 V, I_D = 50 A			105		S
CHARGES, CAPACITANCES & GATE RESISTANCE							
Input Capacitance	C_{ISS}	V_{GS} = 0 V, f = 1 MHz, V_{DS} = 25 V			2200		pF
Output Capacitance	C_{OSS}				900		
Reverse Transfer Capacitance	C_{RSS}				17		
Total Gate Charge	$Q_{G(TOT)}$	V_{GS} = 4.5 V, V_{DS} = 30 V; I_D = 50 A			16		nC
Total Gate Charge	$Q_{G(TOT)}$	V_{GS} = 10 V, V_{DS} = 30 V; I_D = 50 A			34		
Threshold Gate Charge	$Q_{G(TH)}$	V_{GS} = 4.5 V, V_{DS} = 30 V; I_D = 50 A			1.5		
Gate−to−Source Charge	Q_{GS}				5.6		
Gate−to−Drain Charge	Q_{GD}				5.1		
Plateau Voltage	V_{GP}				2.8		V
SWITCHING CHARACTERISTICS (Note 5)							
Turn−On Delay Time	$t_{d(ON)}$	V_{GS} = 4.5 V, V_{DS} = 30 V, I_D = 50 A, R_G = 2.5 Ω			10		ns
Rise Time	t_r				15		
Turn−Off Delay Time	$t_{d(OFF)}$				24		
Fall Time	t_f				5.0		
DRAIN−SOURCE DIODE CHARACTERISTICS							
Forward Diode Voltage	V_{SD}	V_{GS} = 0 V, I_S = 50 A	T_J = 25°C		0.88	1.2	V
			T_J = 125°C		0.78		
Reverse Recovery Time	t_{RR}	V_{GS} = 0 V, dIS/dt = 100 A/μs, I_S = 50 A			41		ns
Charge Time	t_a				21		
Discharge Time	t_b				20		
Reverse Recovery Charge	Q_{RR}				32		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
5. Switching characteristics are independent of operating junction temperatures.
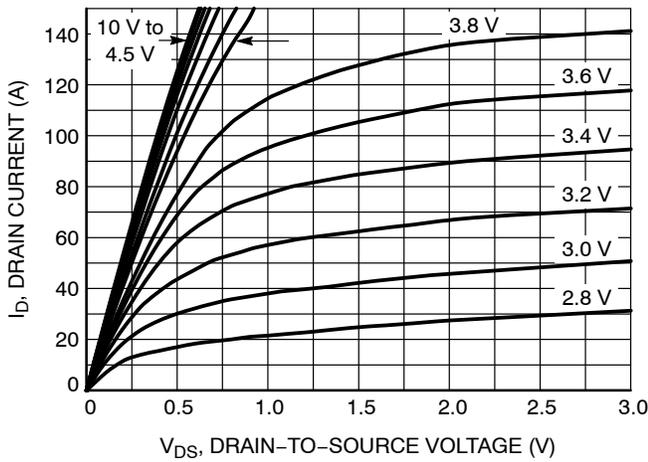
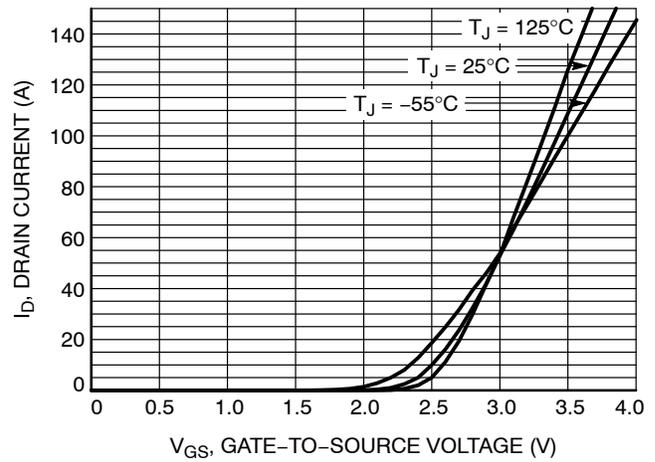## TYPICAL CHARACTERISTICS

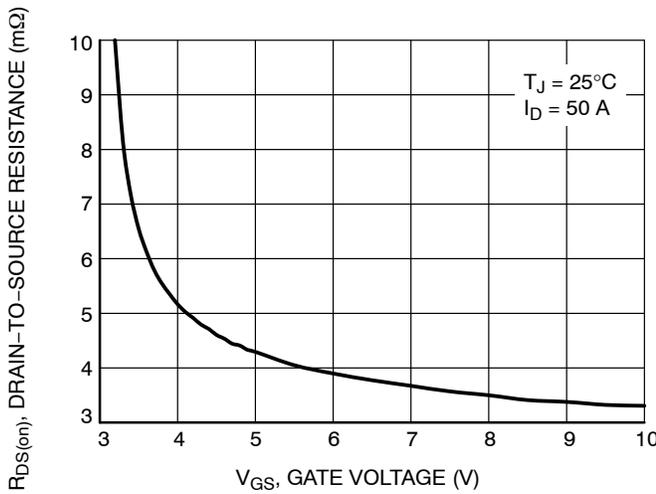**Figure 1. On−Region Characteristics**

Figure 2. Transfer Characteristics

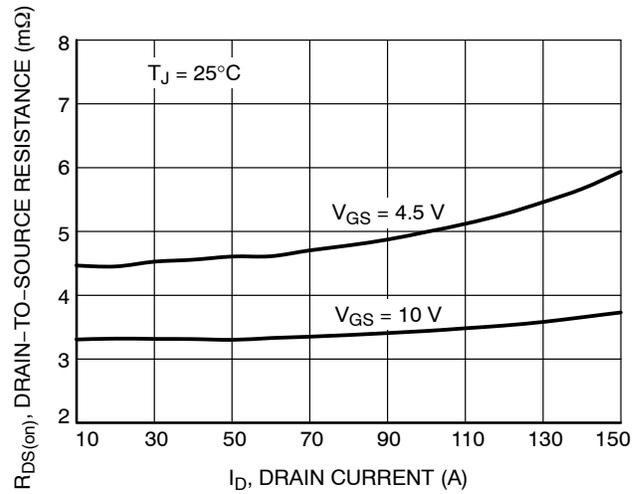**Figure 3. On−Resistance vs. Gate−to−Source Voltage**

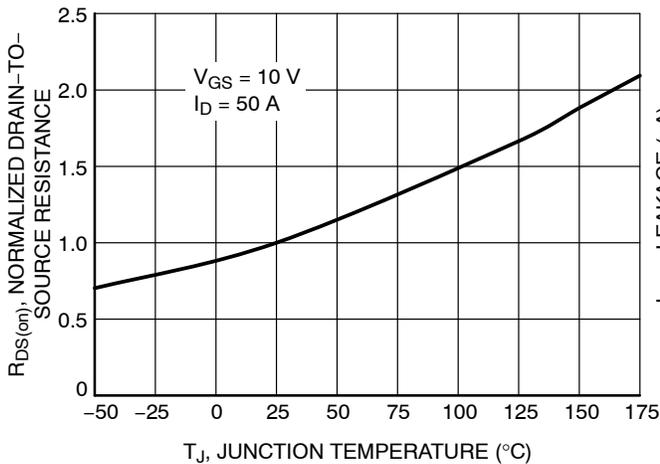**Figure 4. On−Resistance vs. Drain Current and Gate Voltage**

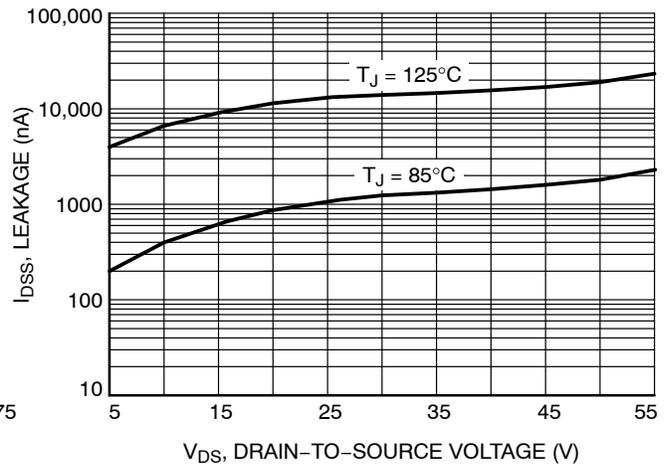**Figure 5. On−Resistance Variation with Temperature**

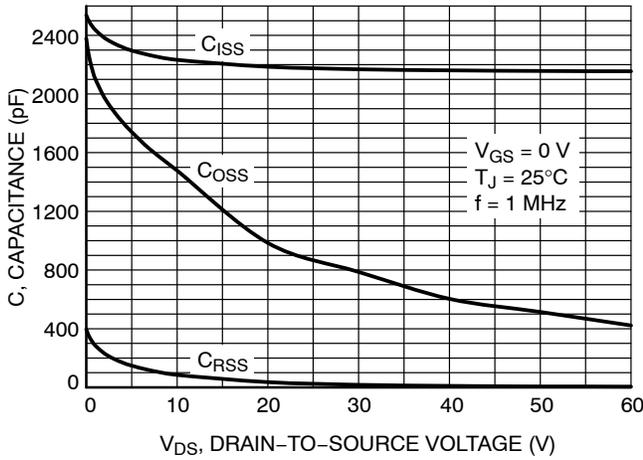**Figure 6. Drain−to−Source Leakage Current vs. Voltage**

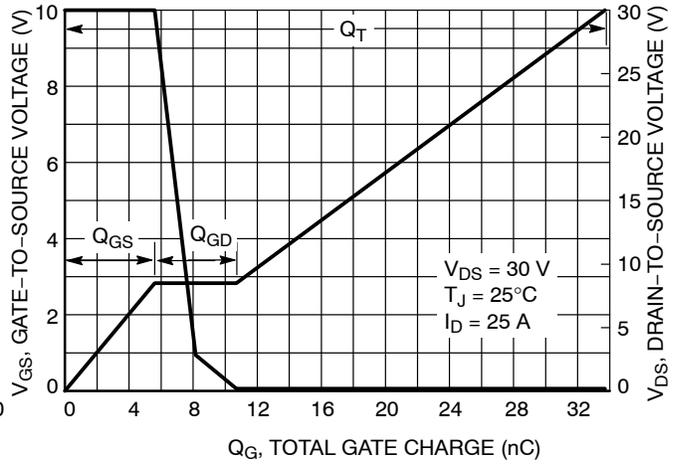## TYPICAL CHARACTERISTICS

Figure 7. Capacitance Variation

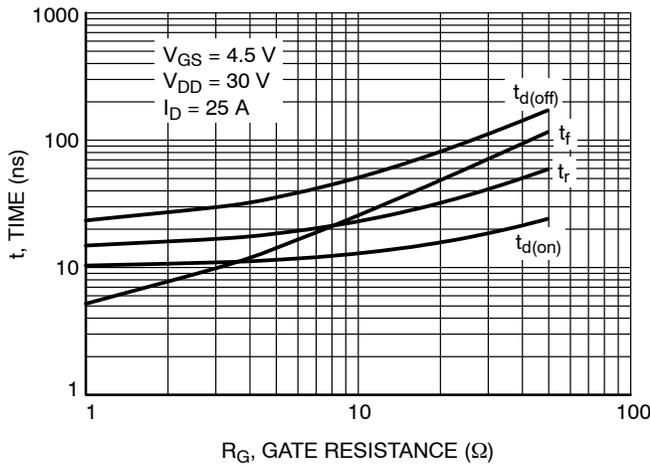Figure 8. Gate–to–Source and
Drain–to–Source Voltage vs. Total Charge

Figure 9. Resistive Switching Time Variation
vs. Gate Resistance
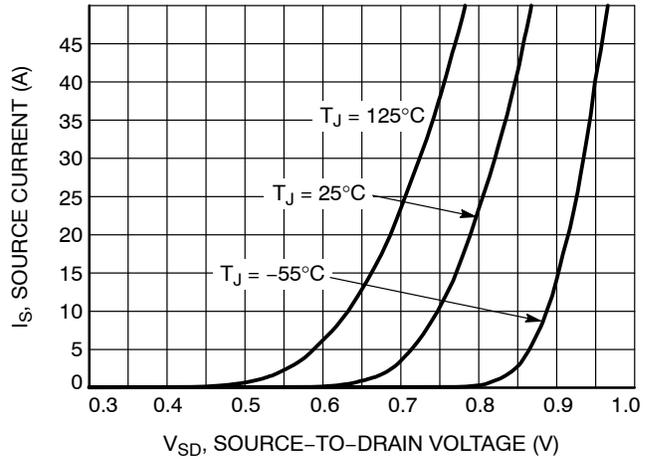
Figure 10. Diode Forward Voltage vs. Current
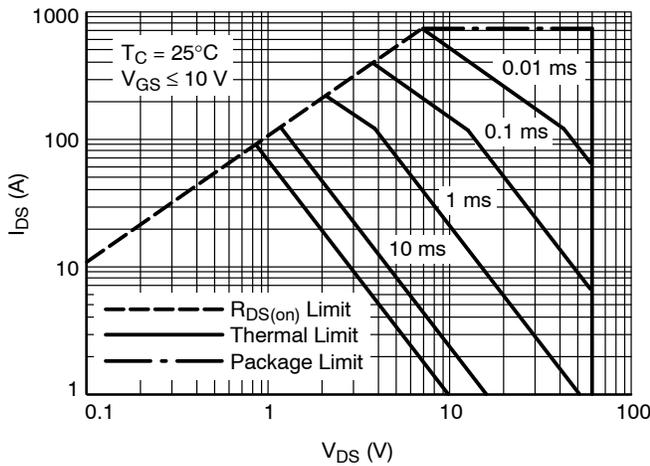
Figure 11. Safe Operating Area
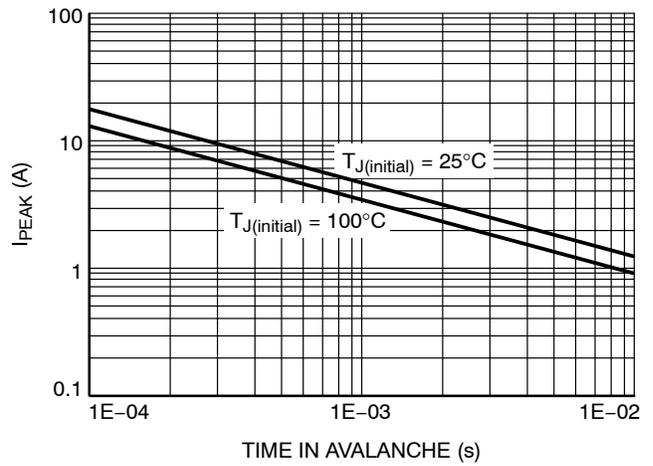
Figure 12. I_{PEAK} vs. Time in Avalanche

TYPICAL CHARACTERISTICS
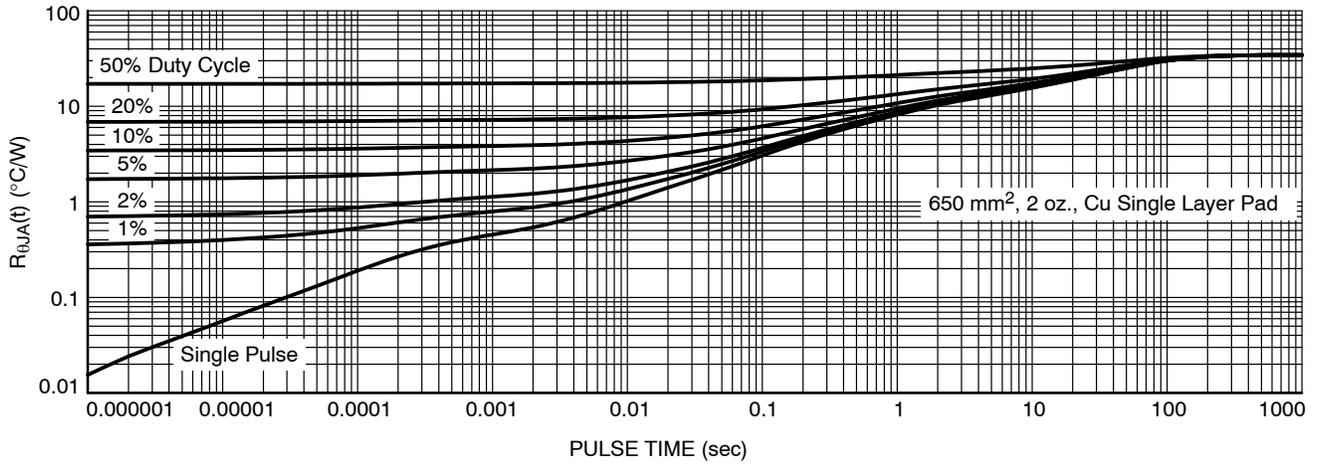
Figure 13. Thermal Characteristics

DEVICE ORDERING INFORMATION

Device	Marking	Package	Shipping[†]
NVMYS4D1N06CLTWG	4D1N06CL	LFPAK4 (Pb–Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

LFPAK4 4.90x4.15x1.15MM, 1.27P
CASE 760AB
ISSUE D

DATE 22 MAY 2024

E | A
b2
B
L1
H
D
(L2)
1 | 4
e | b4 (4x)
e/2 | b (4x)

TOP VIEW

⊕ | 0.25Ⓜ | A

A2
c2
c

SIDE VIEW
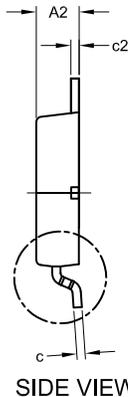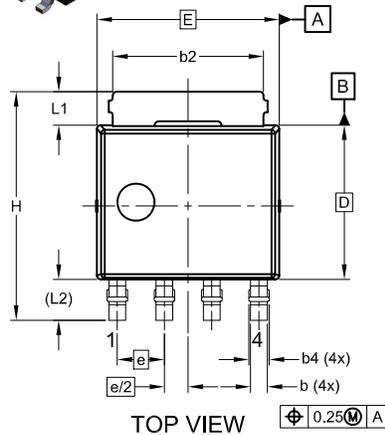
NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2018.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
4. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

A | A3 | C
⌓ | 0.10 | C
A1 | L | Θ

DETAIL 'A'
SCALE: 2:1

E1
E2 | 4
1
D3
D1
D2
D5
D6 | D4
(D7) | (D8)
E3 | E4

BOTTOM VIEW

4.35
3.50
1.30
1.61 | 0.88
0.70 | 0.60
1.06
1.15
1 | 4
0.70 | 1.27
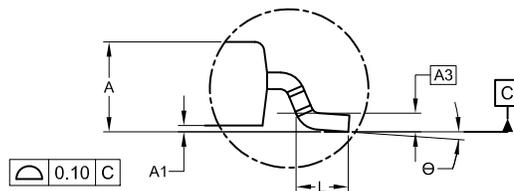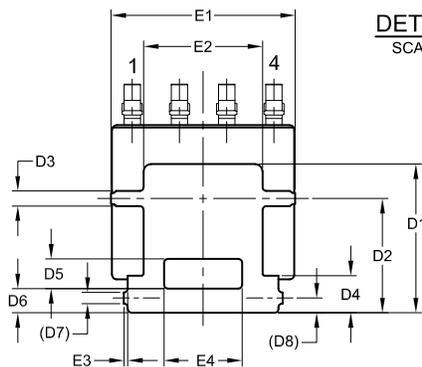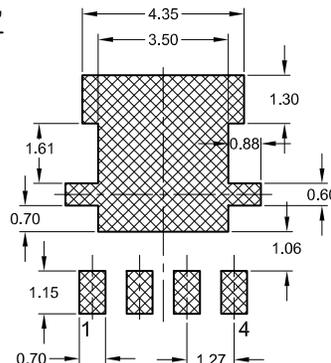
RECOMMENDED LAND PATTERN

*FOR ADDITIONAL INFORMATION ON OUR PB–FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ONSEMI SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

DIM	MILLIMETER		
	MIN	NOM	MAX
A	1.10	1.20	1.30
A1	0.00	0.08	0.15
A2	1.10	1.15	1.20
A3	0.25 BSC		
b	0.40	0.45	0.50
b2	3.80	4.10	4.40
b4	0.45	0.55	0.65
c	0.19	0.22	0.25
c2	0.19	0.22	0.25
D	4.15 BSC		
D1	3.80	4.00	4.20
D2	3.00	3.10	3.20
D3	0.30	0.40	0.50
D4	0.90	1.00	1.10
D5	0.70	0.80	0.90
D6	0.55	0.65	0.75
D7	0.31 REF		
D8	0.40 REF		
E	4.90 BSC		
E1	4.85	4.95	5.05
E2	3.10	3.20	3.30
E3	0.00	0.10	0.20
E4	2.00	2.10	2.20
e	1.27 BSC		
e/2	0.635 BSC		
e1	0.40 REF		
H	6.00	6.15	6.30
L	0.50	0.70	0.90
L1	0.80	0.90	1.00
L2	1.10 REF		
Θ	0°	4°	8°

GENERIC MARKING DIAGRAM*

XXXXXX
XXXXXX
AWLYW
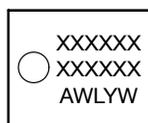
XXXXXX = Specific Device Code
A   = Assembly Location
WL   = Wafer Lot
Y   = Year
W   = Work Week

*This information is generic. Please refer to device data sheet for actual part marking. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98AON82777G	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	LFPAK4 4.90x4.15x1.15MM, 1.27P		PAGE 1 OF 1

ADDITIONAL INFORMATION

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